

Likelihood ratio test, Wilk's thm,  
Goodness of fit etc.

Simple test  $H_0: \theta = \theta_0$   $H_a: \theta = \theta_1$

[as opposed to  $\theta \in \text{Set}$ ]

Turns out that the rejection region  
of most powerful test is of the form

$$\frac{P(D|\theta_1)}{P(D|\theta_0)} > \eta$$

[Neyman-Pearson  
Lemma]

One could consider alternative hypothesis  
to be  $\theta \neq \theta_0$  [Composite case]

Makes sense to choose the rejection  
region to be

$$\frac{P(D|\hat{\theta})}{P(D|\theta_0)} > \eta$$

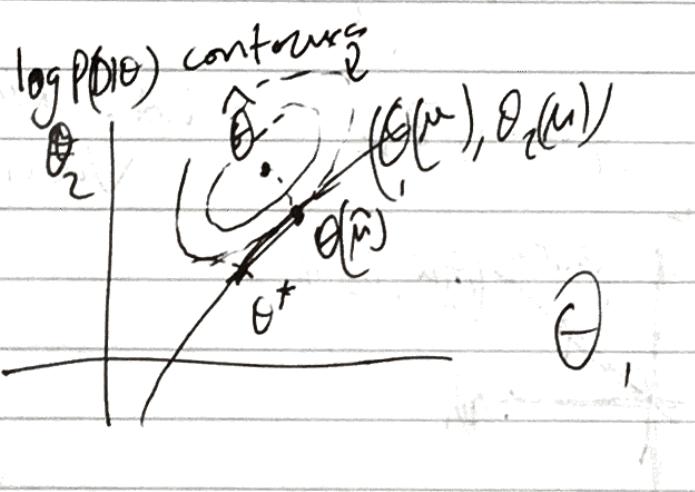
where  $\hat{\theta}$  is  
the MLE

We saw that for  $\boxed{\quad}$  large independent  
samples  $\log P(D|\hat{\theta})/P(D|\theta_0) \sim \chi^2_{n-k}$

where  $K$  is the number of parameters

Interestingly, if we only optimize over a subclass of models  $\Theta(\mu)$ ,  $\mu_1, \dots, \mu_{k'},$  are parameters with  $k' \leq K$

$$2 \log \frac{P(D|\hat{\theta})}{P(D|\Theta(\hat{\mu}))} \sim \chi^2_{K-k'}$$

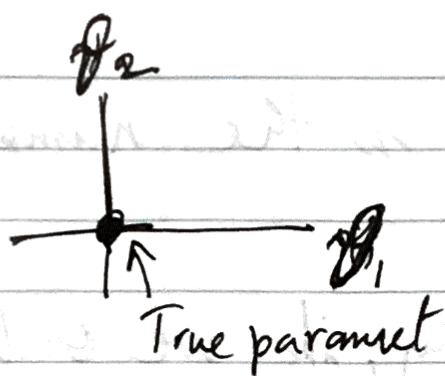


Wilks's  
Theorem!

Basically  $S(D, \theta^*) \approx \frac{1}{n} I(\theta^*)(\hat{\theta} - \theta^*)$

$$E[S(D, \theta^*)] = 0 \quad E[S(D, \theta^*) S(D, \theta^*)] = \frac{1}{n} I(\theta^*)$$

Define  $Z = I_N^{-1/2} S(D, \theta^*)$  and  $J = I_N^{1/2} (\hat{\theta} - \theta^*)$

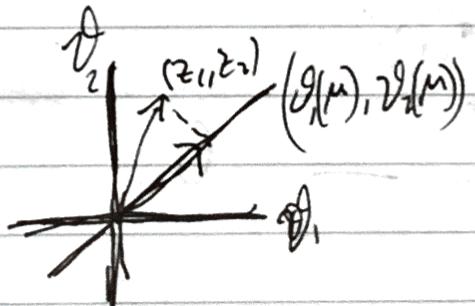


Prob distrn

$$\log \frac{P(D|\theta)}{P(D|\theta^*)} = \frac{s(D, \theta^*)}{\theta - \theta^*} - \frac{1}{2} (\theta - \theta^*)^T J_N(\theta^*) (\theta - \theta^*) + \text{higher order terms}$$

$$= z \cdot \nabla - \frac{1}{2} z^2$$

$z_{11}, \dots, z_k$  i.i.d.  $N(0, 1)$   
Variable



$$z \cdot \nabla_\mu \vartheta = \boxed{\theta} \cdot \nabla_\mu \theta$$

$$z = z_{11} + z_{\perp} \quad z_{\perp} \cdot \nabla_\mu \vartheta = 0$$

$$z_{11} = \hat{g}$$

Trivial example:  $P(D|\theta) = C e^{-\sum (x_i - \mu_i)^2 / 2}$

and  $\mu_i = \bar{x}$  subspace  $2 \log \frac{P(\theta)}{P(D|\theta^*)} = 2 \left( \frac{1}{2} - \frac{1}{2(x-\bar{x})^2} \right) = \sum (x_i - \bar{x})^2$

## Goodness of fit

If we have prob  $\theta_1, \dots, \theta_k$  in a multinomial distribution, and  $N$  observations, we expect  $E_i = N\theta_i$  observation in the  $i$ th category. If we observe only

$O_i$ , then for large  $N$ ,

$$\sum_i \frac{(O_i - E_i)^2}{E_i} \sim \chi^2_{v}$$

when  $v = N - k$

Some cases  $e_i$  are fit from observations  $O_i$ .

In those cases  $v = N - \# \text{ constraints satisfied by } O_i$

$$= N - \# \text{ param's estimated}$$

For example for checking independence

	Success	Failure
cond 1	A	B
cond 2	C	D

$$d.f. = r(c-1) - (r-1) - (c-1) = (r-1)(c-1)$$

for  $2 \times 2$   
d.f. = 1

Reason:  $\frac{N! \prod_i^k \theta_i^{O_i}}{\text{is } O_i!}$   
 ↗ log with Stirling

$$N \log N - N + \sum_i O_i \log \theta_i$$

$$- \sum_i O_i \log \theta_i + \underbrace{\sum_i O_i}_{N} + O(\log N)$$

$$\text{Write } N \log N = \sum_i O_i \log N$$

$$\sum_i O_i \log N \theta_i - \sum_i O_i \log \theta_i \\ = \sum_i O_i \log \frac{\theta_i}{\theta_i} + \dots$$

$$\text{Call } O_i = E_i \delta O_i$$

and expand

$$\sum_i (E_i + \delta O_i) \log \frac{E_i}{E_i + \delta O_i} = \sum_i E_i \left( 1 + \frac{\delta O_i}{E_i} \right) \left( 1 - \frac{\delta O_i + \frac{1}{2} \delta O_i^2}{E_i + \frac{1}{2} \delta O_i^2} \right) \\ = - \sum_i \delta O_i + \sum_i \frac{\delta O_i^2}{E_i} + \dots$$

✓ Adj ( $K-1$ ) param

$$2 \log \frac{P(\hat{D} | \hat{E}_i)}{P(D | E_i(\hat{\mu}))} = \boxed{\text{sketch}} - \frac{1}{2} \sum_{i=1}^K \frac{\delta \hat{O}_i}{E_i(\hat{\mu})}$$

↑ adjust  $k'$  parameters

$$\hat{E}_i = \theta_i \quad \text{df} = K-1-k'$$

Multitesting, Bonferroni Correction, FDR

high throughput exptc  $P(y_i=1 | D) > \tau$

where  $D = \{x_i\}_{i=1}^N$  [Ex: many gene expression modulations]

6000 yeast genes,  $\alpha=1\%$ .  $\boxed{\text{sketch}} \Rightarrow \approx 60$  positives even we have just noise

Prob of 1 False Positive when there is no signal.

$1 - (1-\tau)^N$ . Controlling this is too stringent:

$$1 - (1-\tau)^N = \boxed{\text{sketch}} \quad \alpha = 10\% \quad \text{for } N=6000 \Rightarrow \boxed{\tau} = 1.76 \times 10^{-5}$$

$$[\text{If } \alpha = 1 - (1-\tau)^N \approx N\tau \Rightarrow \tau = \frac{\alpha}{N} = \frac{0.1}{6000} = 1.67 \times 10^{-5}]$$

Too many real signals missed!

Instead, control False Discovery Rate

$$FDR = \frac{FP}{FP+TP} \leq \alpha$$

$$= \frac{FD(\tau, \alpha)}{N(\tau, \alpha)}$$

conclusion	Truth is	
	$H_1$	$H_0$
$H_1$	TP	FP
$H_0$	FN	TN

few walt wyp. random

$\tau$  P-value

Adjust  $\tau$  to achieve  $\alpha$ .

$$FDR \approx \frac{A \cdot \alpha}{N(P_c \cdot P_e)}$$